CITATION IN AN APPLICATION (PTO/SB/O8A)				ATTY. DOCKET NO. 2336-257		U.S. PATENT APPLICATION NO. 10/811,808	
				APPLICANT Seung Wan CHAE et al.			
				FILING DATE March 30, 2004		GROUP 2814	
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EXAMINER		D	1	DATE CONSIDER	ED 12/2	20/06	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.